## E R Kieft

## List of Publications by Year in descending order

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567281 642732 29 555 15 23 citations h-index g-index papers 29 29 29 484 docs citations citing authors all docs times ranked

#	Article	IF	Citations
1	Refinement of Monte Carlo simulations of electron–specimen interaction in low-voltage SEM. Journal Physics D: Applied Physics, 2008, 41, 215310.	2.8	80
2	High quality ultrafast transmission electron microscopy using resonant microwave cavities. Ultramicroscopy, 2018, 188, 85-89.	1.9	50
3	Complementary cathodoluminescence lifetime imaging configurations in a scanning electron microscope. Ultramicroscopy, 2019, 197, 28-38.	1.9	39
4	Discovering Hidden Material Properties of MgCl <sub>2</sub> at Atomic Resolution with Structured Temporal Electron Illumination of Picosecond Time Resolution. Advanced Functional Materials, 2019, 29, 1807818.	14.9	38
5	Time-resolved pinhole camera imaging and extreme ultraviolet spectrometry on a hollow cathode discharge in xenon. Physical Review E, 2003, 68, 056403.	2.1	37
6	Collective Thomson scattering experiments on a tin vapor discharge in the prepinch phase. Physical Review E, 2004, 70, 056413.	2.1	33
7	Communication: Effects of thermionic-gun parameters on operating modes in ultrafast electron microscopy. Structural Dynamics, 2015, 2, 051101.	2.3	33
8	Comparison of experimental and simulated extreme ultraviolet spectra of xenon and tin discharges. Physical Review E, 2005, 71, 036402.	2.1	27
9	Characterization of a vacuum-arc discharge in tin vapor using time-resolved plasma imaging and extreme ultraviolet spectrometry. Physical Review E, 2005, 71, 026409.	2.1	23
10	Stark broadening experiments on a vacuum arc discharge in tin vapor. Physical Review E, 2004, 70, 066402.	2.1	22
11	Subnanosecond Thomson scattering on a vacuum arc discharge in tin vapor. Physical Review E, 2005, 72, 026415.	2.1	22
12	Dual mode microwave deflection cavities for ultrafast electron microscopy. Applied Physics Letters, 2018, 113, .	3.3	21
13	Subnanosecond Thomson scattering setup for space and time resolved measurements with reduced background signal. Review of Scientific Instruments, 2005, 76, 093503.	1.3	20
14	Design and characterization of dielectric filled TM110 microwave cavities for ultrafast electron microscopy. Review of Scientific Instruments, 2019, 90, 083703.	1.3	17
15	Theory and particle tracking simulations of a resonant radiofrequency deflection cavity in TM 110 mode for ultrafast electron microscopy. Ultramicroscopy, 2018, 184, 77-89.	1.9	16
16	Time-of-flight electron energy loss spectroscopy using TM110 deflection cavities. Structural Dynamics, 2016, 3, 054303.	2.3	15
17	Thomson scattering measurements on an atmospheric Ar dc discharge lamp. Journal Physics D: Applied Physics, 2004, 37, 736-743.	2.8	13
18	Pulse length, energy spread, and temporal evolution of electron pulses generated with an ultrafast beam blanker. Structural Dynamics, 2019, 6, 024102.	2.3	9

#	Article	IF	CITATIONS
19	Radicals of Plasma Needle Detected with Fluorescent Probe. , 2005, , 293-308.		7
20	Optoelectronic properties of expanding thermal plasma deposited textured zinc oxide: Effect of aluminum doping. Journal of Electronic Materials, 2006, 35, 711-716.	2.2	7
21	Time-of-flight electron energy loss spectroscopy by longitudinal phase space manipulation with microwave cavities. Structural Dynamics, 2018, 5, 051101.	2.3	7
22	Exploring Functional Materials by Understanding Beamâ€Sample Interactions. Advanced Functional Materials, 2022, 32, .	14.9	7
23	Thomson scattering on high pressure Hg discharge lamps. Journal Physics D: Applied Physics, 2005, 38, 1923-1935.	2.8	6
24	Time resolved Thomson scattering measurements on a high pressure mercury lamp. Journal Physics D: Applied Physics, 2005, 38, 2778-2789.	2.8	4
25	Textured Zinc Oxide by Expanding Thermal Plasma CVD: the Effect of Aluminum Doping. Materials Research Society Symposia Proceedings, 2002, 730, 1.	0.1	1
26	Characterization of highly transient EUV emitting discharges. Journal of Physics: Conference Series, 2006, 44, 90-95.	0.4	1
27	Ultrafast SEM. Microscopy and Microanalysis, 2019, 25, 268-269.	0.4	0
28	Resonant RF Cavity Based Beam Chopping for Precise Control over Electron Arrival Time Distribution. Microscopy and Microanalysis, 2019, 25, 1666-1667.	0.4	0
29	Towards Atomic Resolution Electron Microscopy with Structured Temporal Electron Illumination of Picosecond Time Resolution. Microscopy and Microanalysis, 2019, 25, 1652-1653.	0.4	O